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NASA TECHNICAL Memorandum

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(NASA-TH-X-73436) ENVIRONMENTAL CHARGING OF N76-26261 SPACECRAFT-TESTS OF THERMAL CONTROL MATERIALS FOR USE ON THE GLOBAL POSITIONING SYSTEM FLIGHT SPACE VEHICLE. PART 2: Unclas SPECIME: 6 TO 9 (NASA) 44 p HC \$4.00 G3/18 42402

ENVIRONMENTAL CHARGING OF SPACECRAFT SURFACES - TESTS OF THER MAL CONTROL MATERIALS FOR USE ON THE GLOBAL POSITIONING SYSTEM FLIGHT SPACE VEHICLE -PART 2: SPECIMEN 6 TO 9

by N. John Stevens, Frank D. Berkopec, and Richard A. Blech Lewis Research Center Cleveland, Ohio 44135 June 1976

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16. Abstract			
The NASA/USAF program on t	he Environmental Charging of S	pacecraft Surfaces c	on sists, in
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Global Positioning System Flig	ht Space Vehicles have been tes	ted to determine the	ir response
to electron flux. The primary	result observed was that no dis	charges were obtain	ed with the
quartz-fiber-fabric-covered m	ultilayer insulation specimen.	The taped aluminize	d polyester
grounding system used on all a	specimens did not appear to grou	ssly deteriorate with	time; how-
ever, the specimens require s	pecific external pressure to ma	intain constant groun	ding system
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ENVIRONMENTAL CHARGING OF SPACECRAFT SURFACES - TESTS OF

THERMAL CONTROL MATERIALS FOR USE ON THE GLOBAL

POSITIONING SYSTEM FLIGHT SPACE VEHICLE

PART 2: SPECIMEN 6 TO 9

by N. John Stevens, Frank D. Berkopec, and Richard A. Blech

NATIONAL AERONAUTICS AND SPACE ADMINISTRATION Lewis Research Center Cleveland, Ohio

INTRODUCTION

Several geosynchronous satellites have reported anomalous activity near the local midnight region of the satellite orbits. Concurrent measurements have revealed transient particle fluxes of higher than expected energies in the local evening and midnight sectors of the orbit. Subsequent work has shown correlation between solar substorms and the anomalous behavior of spacecraft. Simple models of the mechanism for spacecraft charging and discharging have been postulated; some engineering fixes have been incorporated in recent satellites. Anomalies persist, however.

A satellite immersed in an ambient plasma will come into electrical equilibrium with that plasma by developing the surface charges necessary to reduce the net current between the satellite and the plasma to zero. The net current consists of contributions from the environmental flux, secondary and backscattered electrons and ions, and photoelectrons from illuminated areas. A satellite with parts in the sun and parts in the shade can be expected to be differentially charged. When adjacent parts are differentially charged such that voltage stress is great enough, breakdown of charged dielectric material occurs. This discharge emits electromagnetic pulses. These electromagnetic pulses are the most likely cause of satellite anomalous activity. Other results of discharges are the degradation of thermal control surfaces, surface contamination, and unwanted fields.

As a result of these problems the NASA and the Air Force initiated a joint research and technology program on the environmental charging of spacecraft surfaces that consists of analytical and experimental efforts directed to ultimately result in a spacecraft charging design and test monograph. The analytical effort is being conducted to model the environment and to investigate the charging and discharging mechanisms. The experimental effort is being conducted to evaluate the response of materials to the environmental charged particle flux. Specific experimental efforts conducted as part of this program include the testing described in this report. This report presents the results of environmental charging tests performed on test specimens of thermal control multilayer insulation blankets of the type to be used on the Global Positioning System Flight Space Vehicles. The specimens were supplied by the Rockwell International Corporation and the testing was performed in response to a request by the Rockwell International Corporation through the Air Force.

Test data consists of the magnitude of test specimen leakage current with the test specimen in a representative electron environment and a count of the discharges (of a certain magnitude) that occur on the specimen. The electron environment is deemed to be both the most severe and the most informative environment to pursue. The discharges are discriminated as described in the Appendix.

The Global Positioning System Flight Space Vehicles will be nominally in a 10,989 nautical mile orbit with an inclination of 63 degrees. While environmental charging of spacecraft surfaces has been specifically identified at geosynchronous orbit, the possibility exists that the phenomena can be encountered at lower orbits. The environment at lower orbits is sufficiently unknown to justify the testing reported herein.

APPARATUS AND PROCEDURE

Specimens Tested *

<u>Specimen 6.</u> - This is a multilayer insulation blanket with a 0.0127cm (5 mil) aluminized Kapton outer sheet, Kapton surface facing outward, and 15 layers of 0.00064cm (1/4 mil) single aluminized Mylar. The layers of the blanket are grounded by means of a grounding system that consists of polyester film strips and a wire bonding jumper. The strips are aluminized on both sides and are 0.00064cm (1/4 mil) thick and 2.54cm (1 in.) wide. A strip is taped to each metalized layer of the blanket. The strips are then brought out to the bonding jumper, which is terminated in a lug, and attached to the jumper by means of a compression assembly consisting of washers and a grommet. Electrical continuity throughout the entire grounding system is maintained by means of contact pressure.

<u>Specimen 7</u>. - This is identical to Specimen 6 except that the outer sheet is aluminized Teflon.

<u>Specimen 8</u>. - This is identical to Specimen 6 except that the outer sheet consists of a quartz fiber fabric.

- * Specimens 1, 2, 3, 4, and 5 have been previously tested; the results are reported in a companion publication.
- / These polyester film strips are Mylar polyester.

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<u>Specimen 9</u>. - This is similar to Specimen 6 except that the multilayer insulation consists of 15 layers of 0.00064cm (1/4 mil) aluminized (one side) Kapton separated by nylon mesh. Grounding is obtained in the manner described for Specimen 6.

Facility

The facility, instrumentation, and test procedure are described in Appendix 1 of this report.

Electron Beam Calibration

The electron beam at the specimen location was mapped with a five probe rake. This rake consisted of five current probes spaced horizontally 15.2cm (6 inches) apart with the center probe centered on the sample. The rake was moved vertically through the beam. Current readings were taken every 7.6cm (3 in.) from 38.1cm (15 inches) above specimen center to 38.1cm (15 inches) below specimen center.

Contour plots of current density at the nominal specimen plane were made from the data obtained. These are based on linear interpolation between the data points and show beam contours at the test conditions. A typical current density contour plot is shown in figure 1.

Resistance Measurements

In addition to the measurements described in the appendix of this report, the resistance of each multilayer insulation blanket was measured from the ground attachment point to various points on the aluminum surfaces of the blanket assemblies. These measurements were made before and after each test sequence.

RESULTS

The data from these tests are of two types: that which is taken when no discharges are occurring, and that which is taken when they are occurring.

When no discharges occur, the specimen current is obtained as a function of time, and in general the specimen current reaches a steady-state leakage current. A representative value of leakage current was chosen from each survey and converted to current per unit area of specimen. This is presented in Table 1. The individual plots of specimen current as a function of time for various beam voltages are presented in figures 2, 3, and 4 for Specimen 6, figures 8, 9 and 10 for Specimen 7, figures 13, 14, 15, 16, 17 and 18 for Specimen 8, and figures 19, 20, and 21 for Specimen 9. The data obtained when discharges are occurring is the number of discharges per unit time. This is plotted both cumulatively and directly. The individual plots of discharge activity are presented as the cumulative number of discharges per unit time in figure 7 for Specimen 6, figure 12 for Specimen 7, and figure 22 for Specimen 9. The plots of discharges per unit time are presented in figures 5 and 6 for Specimen 6, figure 11 for Specimen 7, and figures 23 and 24 for Specimen 9.

Table 2 presents the resistances measured between various points of the blanket assemblies.

DISCUSSION

Visual Observations of Testing

Discharges did not occur at any test current density until a beam voltage of 12kV was reached. This is in agreement with past experience. Specimen 8, the quartz-fiber-fabric covered multilayer insulation, did not discharge. Specimen 8 was observed to electrofluoresce. Specimen 6 and 9 exhibited "glow" type discharges. Time exposure photographs revealed small "pinpoint" discharges along the thread on the edge of the specimens. See figure 25. These discharges appeared as a concentration of the "glow" along the edges. Specimen 7 appeared to exhibit "glow" discharges with concentrated areas of light within the "glow". Photographs showed some discharges on this sample to consist of a group of "lightning" type discharges with streamers running between the outgassing holes in the blanket outer sheet; see figure 26.

Grounding Technique

The results of resistance measurements are presented in Table 2. Performing the measurements was a difficult procedure; the resistance was dependent upon arbitrary movement of the grounding strap and locally applied pressure. No specific conclusions concerning grounding system degradation can be stated; however, the grounding system did not appear to grossly deteriorate with time. It is therefore recommended that each specimen be disassembled and closely examined for any evidence of degradation.

Leakage Current

Individual plots of leakage current data for Specimens 6, 7, and 9 show the general trends of polymeric films in the NASA-LeRC test chamber simulation of the electron environment. The plots in figure 2 are typical. The intial charging of the specimens by the incident beam occurs in several minutes; shorter charging times are observed with higher flux. Steady-state leakage current is usually attained in minutes but tests are continued to 20 minutes to insure that a steady state is observed and sufficient data is obtained.

The leakage current plots for Specimen 8 are typical for materials that do not charge in the simulated environment. The leakage current is constant with time and increases with increasing incident flux. Note that differences in sample and probe areas exist; the sample area is 930cm² but the flux is measured by means of a 100cm² probe. Also, there is some beam nonuniformity in the sample plane; see figure 1.

Discharges

Table 1 presents leakage current data for those values of electron beam voltage for which no discharges were observed. It can be seen that discharges did not begin to occur until 10kV had been exceeded. This is in agreement with past experience. Individual plots of discharge count data show typical and not unexpected trends: increasing discharge counts with increasing beam voltage and increasing beam current.

SUMMARY OF RESULTS

Environmental charging tests have been performed on samples of thermal control materials for the Global Positioning System Flight Space Vehicles. These tests have shown the quartz-fiber-fabric covered multilayer insulation to be free of charging and the attendant discharges in the simulated environment. The polymeric-fiber covered multilayer insulation specimens charged and discharged in the conventional manner; discharges were observed at beam voltages in excess of lOkV. The resistance of the grounding system of each specimen was difficult to measure and no specific conclusion regarding the integrity of the grounds can be stated. It is recommended that each specimen be disassembled and examined for evidence of degradation.

AUTHORS' STATEMENT

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Current practice in the field of spacecraft thermal control involves use of <u>specific</u> materials. Trade names and similar identifications cannot be replaced by adequately descriptive generic terms. Trade names, therefore, have been used in this report. Thus, reference has been made to Kapton, Teflon, and Mylar, plastic films produced by the E. I. duPont deNemours & Co., Inc.

The quartz fiber fabric was provided to the Rockwell International Corporation for their thermal blanket specimen by the Air Force Materials Laboratory.

	Incident Current Density	<u>Specimen Leakage Current Density (nA/cm²)</u> Beam Voltage (kV)							
<u>Specimen</u>	(nA/ cm ²)	5	8	10	12	14	16	18	20
Specimen 6, Kapton/Mylar MLI**	0.50 1.0 3.0	0.17 0.34 0.90	0.17 0.34 1.0	· · · /	*				
Specimen 7, Teflon/Mylar MLI	0.50 1.0 3.0	0.19 0.17 0.60	•	0.22					
Specimen 8, Quartz Fiber Fabric/Mylar MLI	0.50 1.0 3.0	0.40 0.69 2.1	0.46 0.81 2.5	0.80	- •	0.50 0.73 2.5	••		0.50 0.80 2.5
Specimen 9, Kapton/Kapton-Nylon Net MLI	0.50 1.0 3.0	0.15 0.29 0.82	0.15 0.28 0.81	0.13 0.27 0.78					

Table 1. - Summary of Specimen Leakage Current per Unit Specimen Area

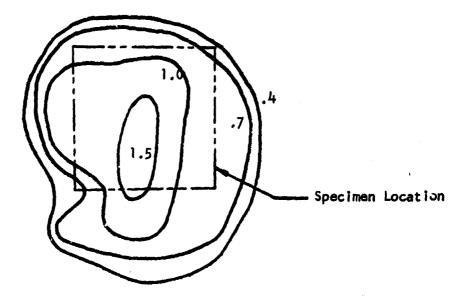
* Each absence of data is due to specimen discharging. The frequency of discharging prevented the measurement of steady state leakage current.

*** MLI:Multilayer Insulation

Table 2, -	Specimen	Grounding	System	Resistance
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Specimen	Point of Measurement to Bonding Jumper Terminal Lug	<u>Resistance (ohms)</u> Before After Test Test		
Specimen 6, Kapton/Mylar MLI*	Aluminized side of outer sheet Foil edges: Front edges Back edges Aluminized side of back sheet	50 50 50-70 20-30	0pen 10-70 0pen 50	
Specimen 7, Teflon/Mylar MLI	Aluminized side of outer sheet Foil edges: Front edges, top (strap) Front edges, sides and bottoms Aluminized side of back sheet	0pen 2 0pen 5	0pen 25 25 20	
Specimen 8, Quartz Fiber Fabric/Mylar MLI	Foil edges: all Aluminized side of back sheet	30 30	25 25	
Specimen 9, Kapton/Kapton- Nylon Net MLI	Aluminized side of cater sheet Foil edges: all Aluminized side of back sheet	40 Open Open	10,000 Open Open	

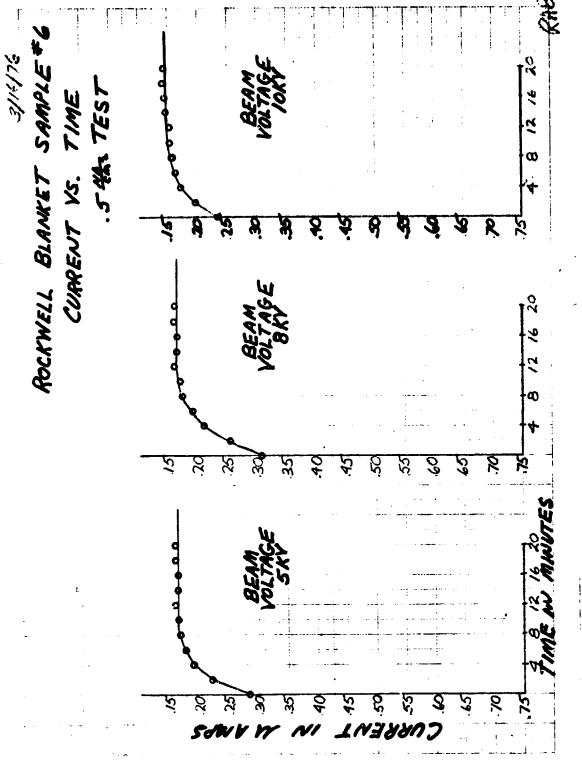
* MLI:Multilayer Insulation



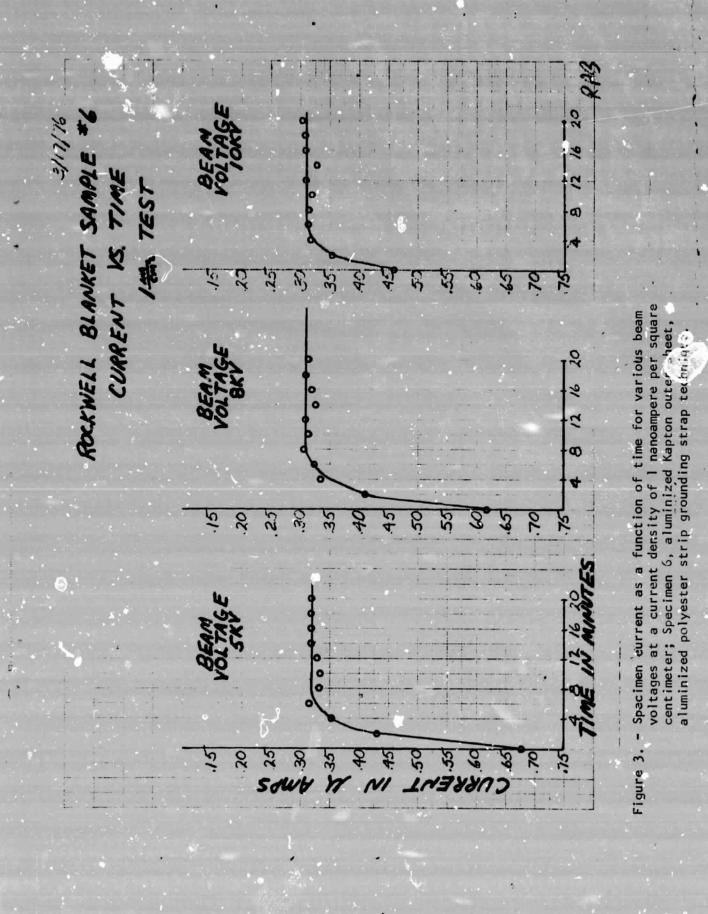
Data is nanoamperes per square centimeter

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Figure 1. - Typical electron beam current density in the specimen plane.



voltages at a current density of .5 nanoampere per square - Specimen current as a function of time for various beam centimeter; Specimen 6, aluminized Kapton outer sheet aluminized polyester strip grounding strap technique. Figure 2.



(1)3 ... 12 16 20 Rockwell Blankat Sample #6 Current 1/2 time 10/1 0 00 3"Xm2 lest 4 09. 00. .80 1.00 1.10 1.40 1.50 1.60 1.70 120 8 1.80 2. beam voltages at a current density of 3 nanoamperes per square centimeter; Specimen 6, aluminized Kapton outer sheet, aluminized polyester strip grounding Specimen current as a function of time for various 12 16 20 0 00 40 4 \$ 8 1.10 8 50 8 170 100% -80 1.20 20 6. 140 12 16 20 Time in Minutes 0 strap technique. skl 0 0 0 00 0 4 0 Figure 4. -ליאטריד רחצעריד 09-(stap /) 3 1.70 3 30 2. 8

3/13/76 Rockwell Blanket Sample #6 Discharge Coart a Function of 45 Time, BEAM Voltage and CURRENt DENsity. CURRENT 16KV IstV 124V ZOKV DENSIL Discharges Greater than 2.5 Kilts 00 00 00 0 D 40 160 60 100 120 140 80 1211 10 00 CURRENT 20HV 16KV 18kV 124 0000 00 0 40 60 120 160 80 100 100 Minutes TIME IN

Figure 5. - Discharge count as a function of time for various beam voltages and current densities; Specimen 6, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

Rockwell Blanket Sample #6 DischARGE Count AS A FUNCTION OF TIME, BEAM Voltage & CURRENT DENsity Current Density . 5 Man DISCHARGES > 2.5 VOL 73 16kV MAKV 18kV ZOKY 3/16/76 1244 0 00 00000 60 40 80 160 TIME IN MINUTES

Figure 6. - Discharge count as a function of time for various beam voltages at a current density of .5 nanoampere per square centimeter; Specimen 6, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

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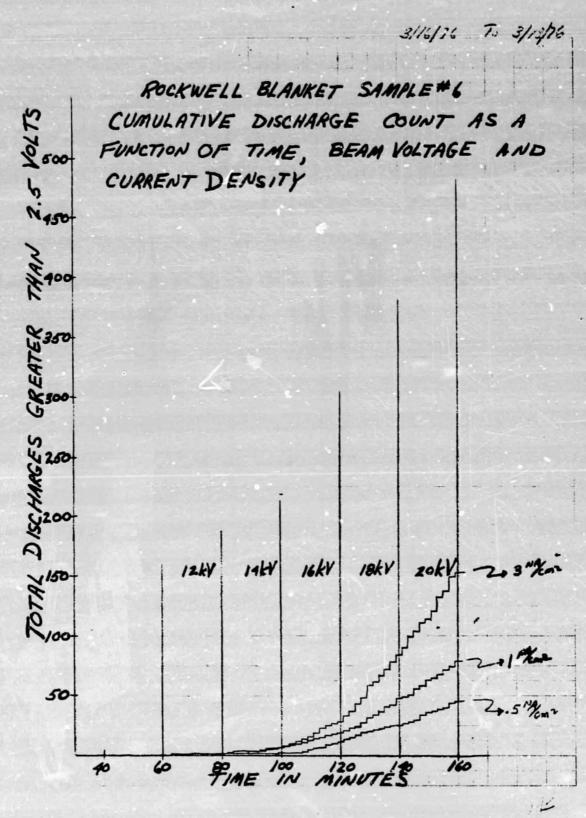


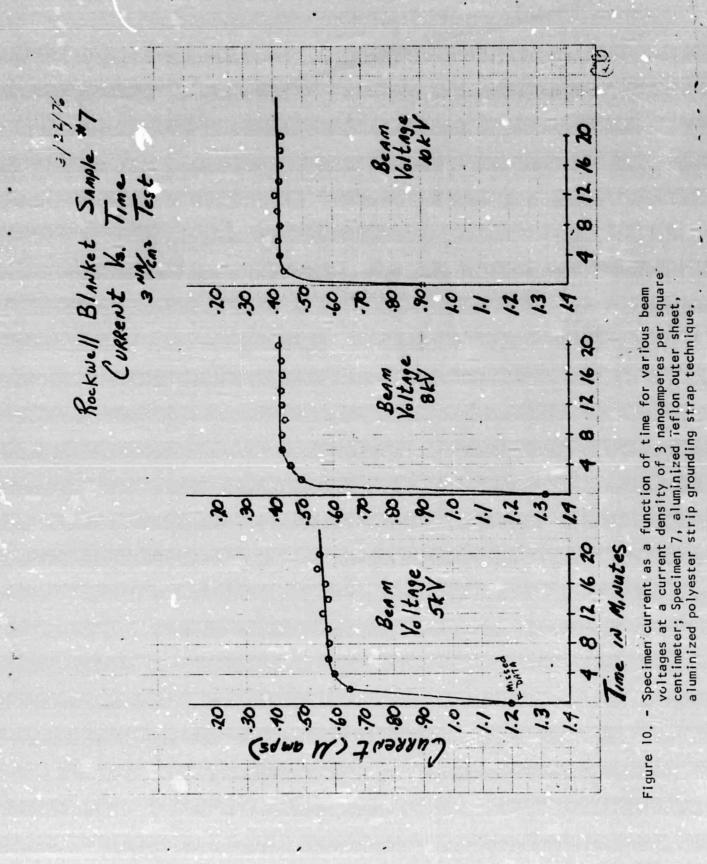
Figure 7. - Cumulative discharge count as a function of time for various beam woltages and current densities; Specimen 6, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

60 1 3. Ample #7 Test Bear Veltinge 3/19/76 R 12 16 5 WEme 8 Rockwell Blanket CURRENT /s. 4 voltages at a current density of .5 nanoampere per square Specimen corrent as a function of time for various beam \$.45 oL. .20 centimeter; Specimen 7, aluminized Teflon outer sheet, 50 09. .15 25 8 35 -55 -65 52. aluminized polyester strip grounding strap technique. 12 16 20 84 8 4 Q. .63. 25 ß 351 .15 -20 09-2. ß 5 33 ÿ 4 8 12 16 20. Time an Munutes lelt age Beam 0 1 2.30 109. 52.00 しょう URRent .50 5 .15 02. 3 Figure 8.

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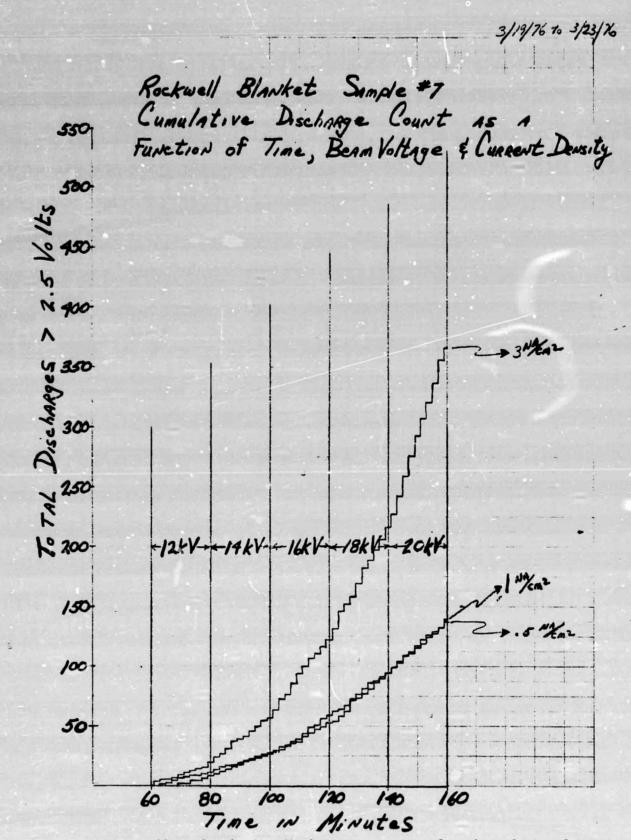
10 Bean Voltage Rockwell Blanket Sample #7 CURRENT & Time 31:12 20 8 12 16 /est 1 mene 4 9 .45 es. voltages at a current density of 1 nanoampere per square 5 99 2. な .20 8 ŝ 5. 52 ઝુ Figure 9. - Specimen current as a function of time for various beam centimeter; Specimen 7, aluminized Teflon outer sheet, aluminized polyester strip gounding strap technique. 8 12 16 20 Beam 4 .20 كن ŝ 53 Ŗ Time in Minutes 5 8 3 3 θ, 3 .15 4 8 12 16 20 2 1.25 los () .65 (soubs) 53 60 2 28850 2. 51.

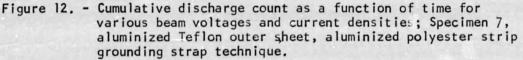
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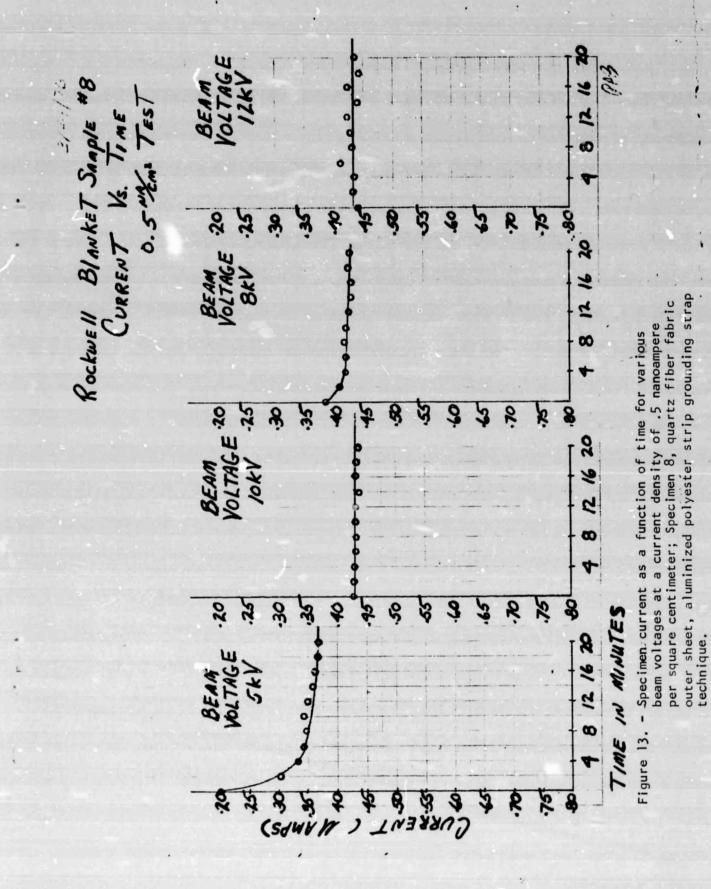


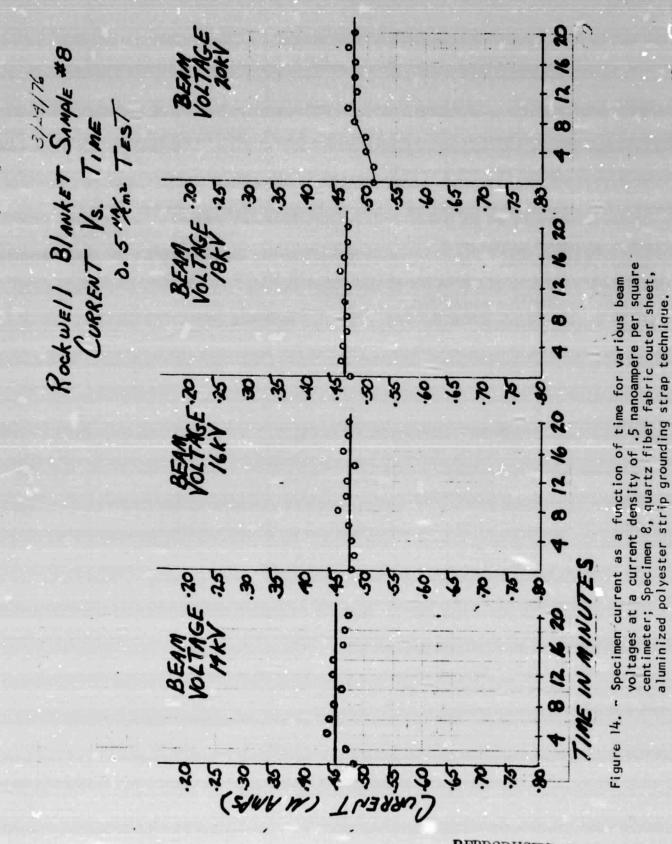
Rockwell Blanket Sample #7 Discharge Count FUNCTION AS of Time, Beam Voltage And Vensity CURRENT. 2.5 VOLTS °rsk V zotV 12KV HAKV 16 K) Unent Density 80 0 0000 THAR 3/19/76 KO 100 120 140 60 GREATER 18 kV CURRENT zakV 12kV 14KY Dennity 0 Enz 000 3/19/76 00 AJI D 00 00 00 0 000 000 0 3/22/76 ARGES 60 100 160 120 30 KHV 18KV 12KV MEV zokV 25 CURRENt 20 15 10 6 3/22/76 0 5 000 8 00 3/23/76 140 160 120 Figure 11. - Discharge count as a function of time for various? beam voltages and current densities; Specimen 7, aluminized Teflon outer sheet, aluminized polyester

strip grounding strap technique.

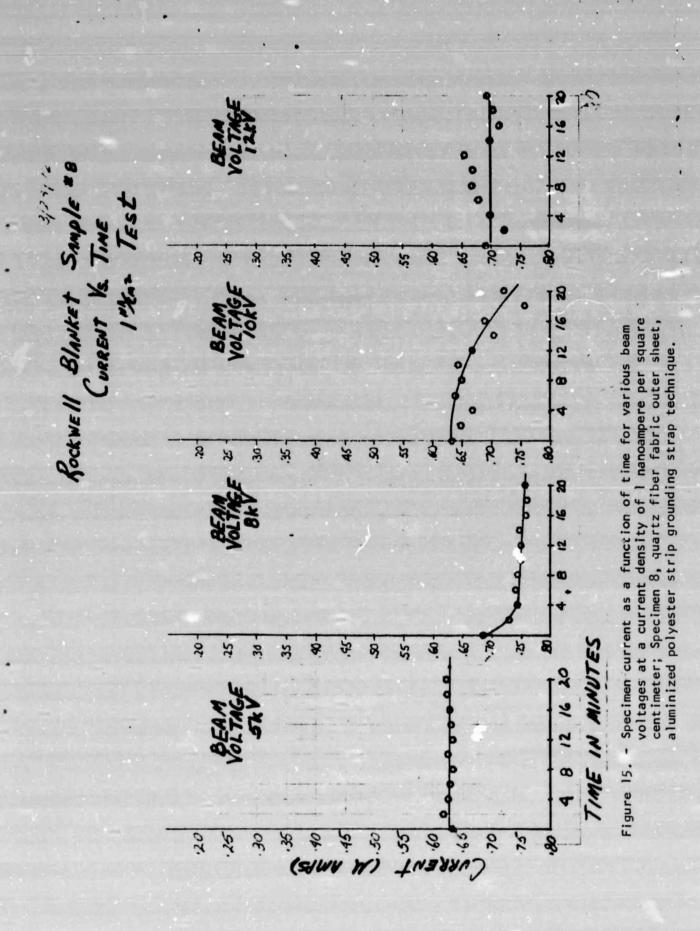


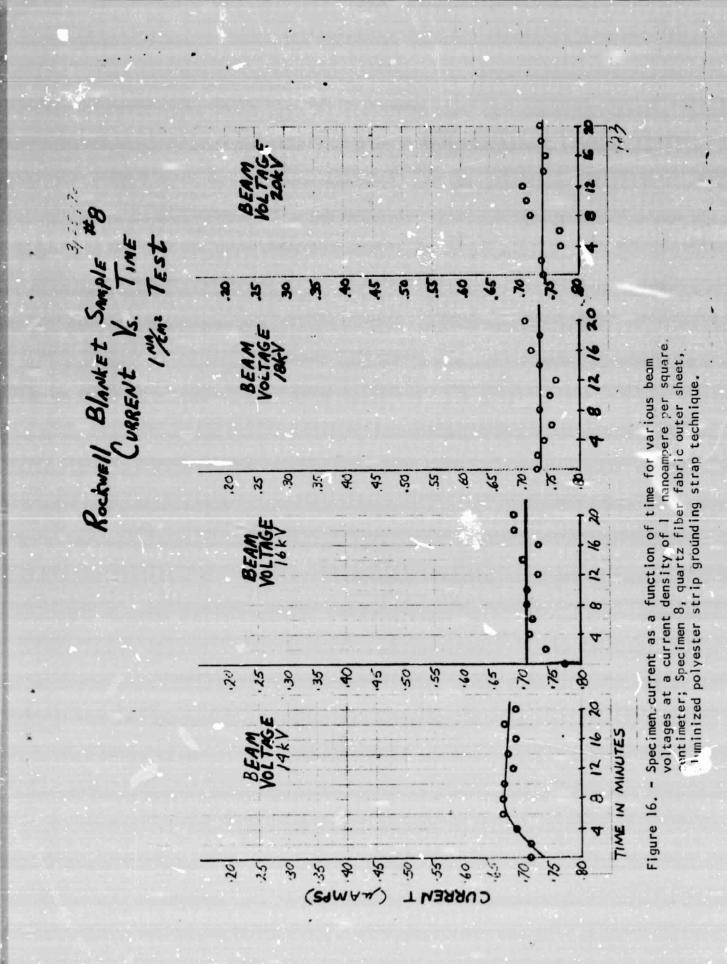


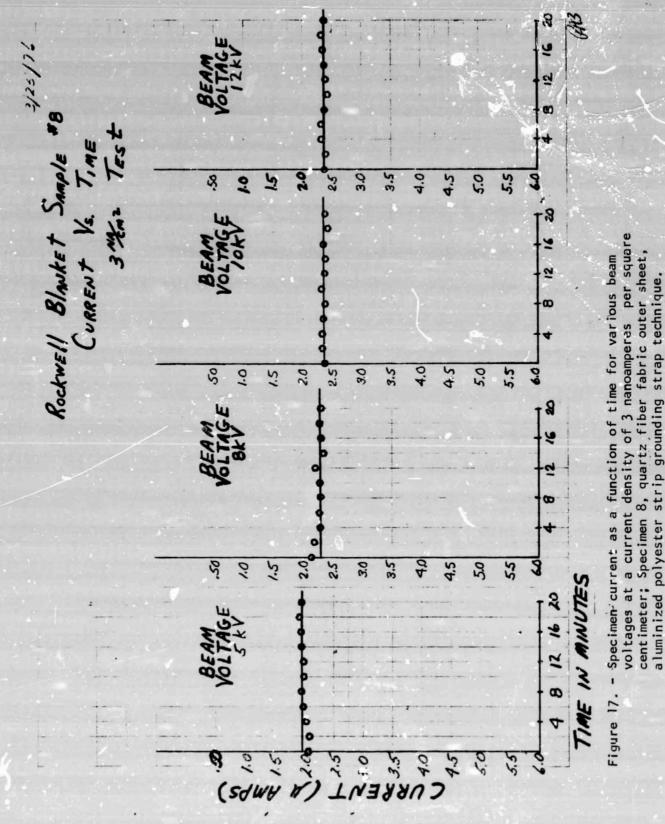




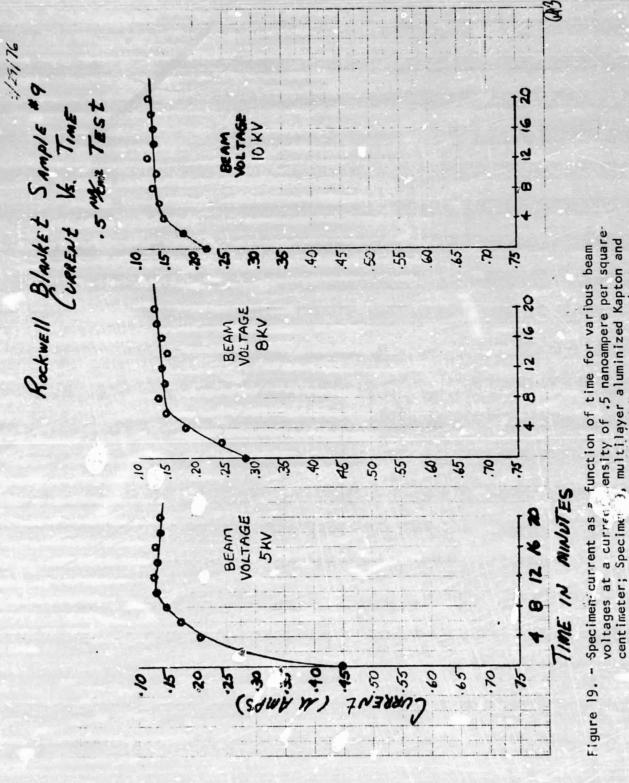
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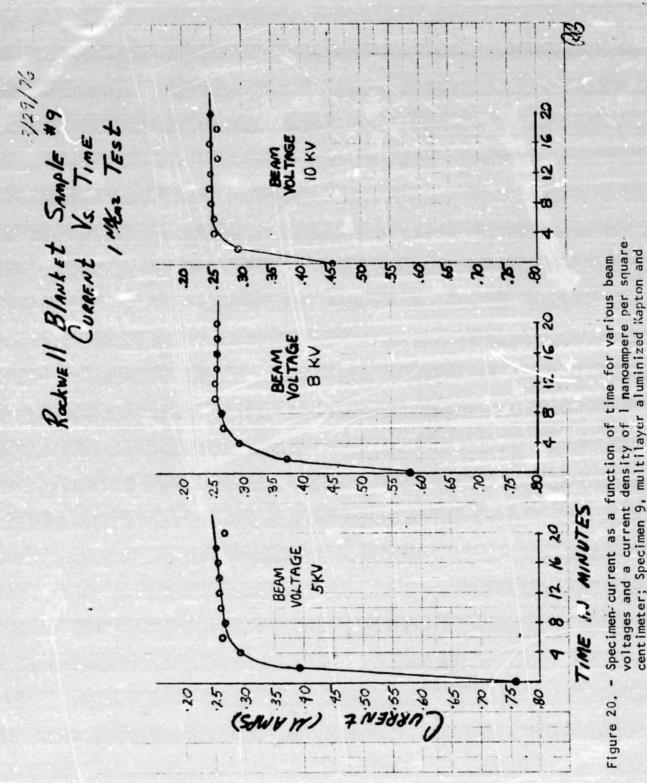
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nylon mesh insulation, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.



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centimeter; Specimen 9, multilayer aluminized Kapton and nylon mesh insulation, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

Cha3 \$ 170 6.# 2 Kackwell Blanket Sample CURRENT & TIME 2 3 2 4 00 6 voltages and a current density of 3 nanoamperes per square centimeter; Specimen 9, multilayer aluminized Kapton and Figure 21. - Specimen current as a function of time for various beam 3 8 2.0 ę 3 0 24 2 6. T aluminized polyester strip grounding strap technique. nylon mesh insulation, aluminized Kapton outer sheet, 8 12 16 20 â 8 3.6 \$ 0 0.2 2.2 2.1 N TIME IN MINUTES 04 11 18 4 027 8 UNEN !! 2.2 SWYN Ì

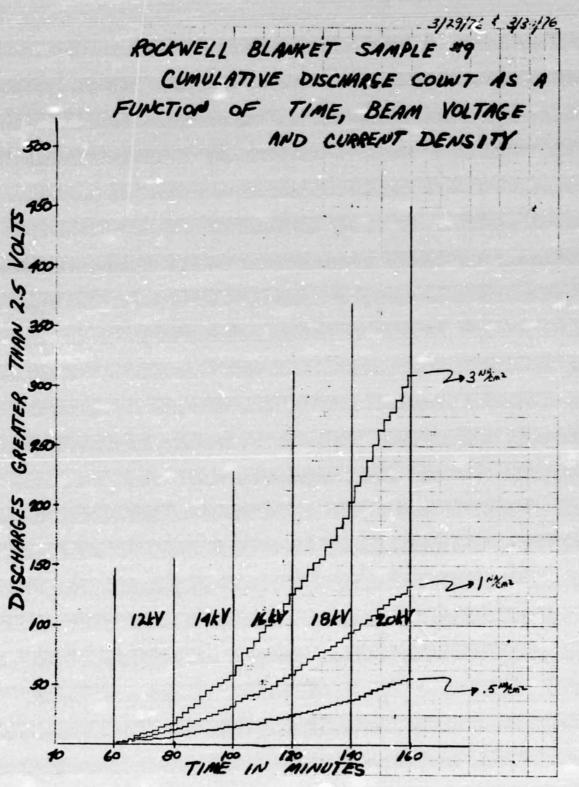
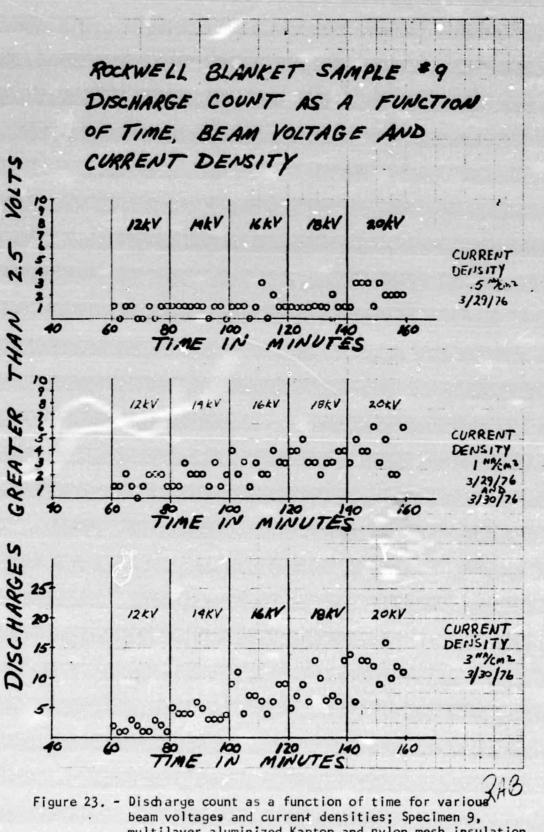


Figure 22. - Cumulative discharge count as a function of time for various beam voltages and current densities; Specimen 9, multilayer aluminized Kapton and nylon mesh insulation, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

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multilayer aluminized Kapton and nylon mesh insulation, aluminized Kapton outer sheet, aluminized polyester strip grounding strap technique.

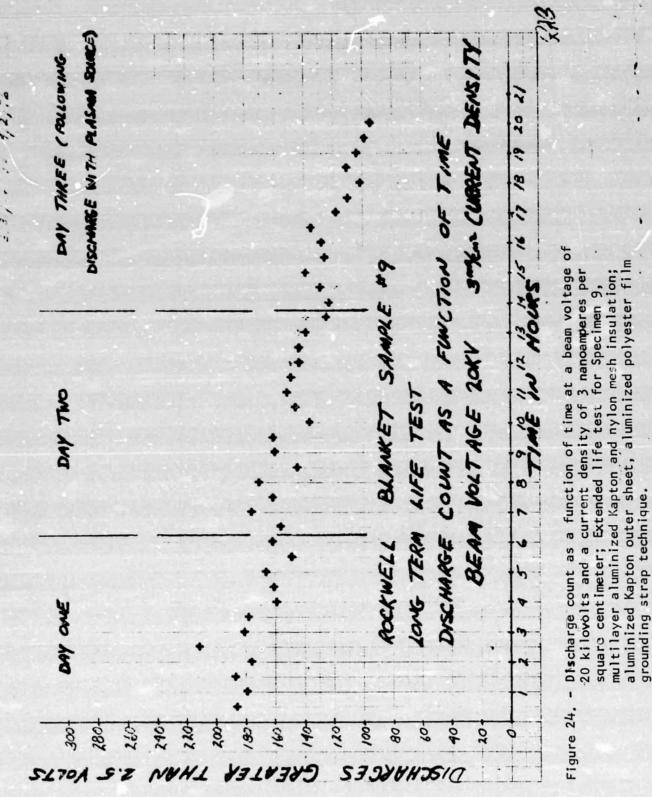


Figure 25. - Specimen 9, multilayer aluminized Kapton and mylon mesh insulation, aluminized polyester strip grounding strap technique; discharges along thread on the border at a beam voltage of 20 kilovolots and a current density of 3 nanoamperes per square centimeter, time exposure 1 hour. Taken during the 20 hour life test.

Bright spots in vent holes are from accumulated discharges. The dark vent holes(strip at top center) are over the grounding strap

Figure 26. - Specimen 7, aluminized Teflon outer sheet, aluminized polyester strip grounding strap technique; "lightning" type discharges at a beam voltage of 20 kilovolts and a current density of 3 nanoamperes per square centimeter, time exposure 5 minutes.



cing at a beam voltage of 16 kilovolts and a current density of 1 nanoampere per square centimeter, time exposure 20 minutes.

APPENDIX I

TEST PROCEDURS

1.0 SCOPE

This test defines the procedure used to survey the characteristics of materials (primarily insulators) exposed to fluxes of high voltage electrons. This procedure applies to short term testing at various electron beam voltages and current densities as well as any extended duration testing at a given beam voltage level.

2.0 TEST FACILITY

The test facility is shown schematically in Figure 1. The tests are performed in a 1.8 meter diameter by 1.8 meter long (6 ft. diameter x 6 ft. long) vacuum chamber capable of operating at a pressure of about 1×10^{-7} torr using conventional diffusion pumping. The grounded, conductive wall forms a boundary condition for all tests.

The primary elements of the test facility are the electron beam gun, the test sample, and the charge-discharge instrumentation.

A divergent electron beam is generated from a hot wire filament by means of a curved accelerating screen. The filament is biased to the desired voltage level while the accelerating screen is kept at ground potential. The electron beam gun is surrounded by a ground screen to minimize any stray electric fields from the high voltage system. Hence, the electron beam enters a grounded chamber and is influenced only by the surface being charged. The gun is designed to produce a uniform beam at the test plane about one meter from the gun exit plane. A typical current density profile at the test plane is shown in Figure 2.

The test sample is located on the gun centerline about one meter from the gun. The nominal size of the test sample is 17cm x 20cm and the sample is mounted normal to the electron beam. Sample sizes up to 30cm x 30cm can be readily accommodated in this facility. The substrate (or any other selected ground surface) is brought to ground by means of a coaxial cable through a digital electrometer. The output of this instrument is connected to an oscillograph. The purpose of this system is to monitor the leakage current during a test. The test instrumentation consists of the current sensors, loop antennas, oscillograph, arc counter, oscilloscopes, and the photographic system. Four current sensors (plain metal discs) surround the test sample to permit continuous monitoring of the beam current during testing. A fifth sensor is mounted on a 30cm x 30cm grounded plate which is centered over the sample at the start of each test phase to determine the current density. The plate keeps the test sample from being charged until the sensor is raised, exposing the sample to the electron flux and signaling the start of a test. The beam current density can be checked periodically during the test by lowering this sensor.

There are two 15cm diameter loop antennas in the facility mounted about 33cm from the test sample. The plane of the loop points towards the center of the sample. One of the antennas is connected to a fast storage oscilloscope using coaxial cable with a 50 ohm termination. This oscilloscope monitors the discharge activity. The data is recorded photographically for permanent record. The second antenna is connected to an arc counter that is activated by any discharge that produces a pulse greater than $2\frac{1}{2}$ volts in the antenna. The counts are recorded manually by the operato during the test.

The lead from the test sample to ground can be switched to bypass the electrometer and its associated arc protection circuitry. This shorted lead is used to monitor the transients in the current to ground introduced by surface discharges. A current probe is connected to the lead and read on a fast storage oscilloscope. The data is photographed for permanent record.

The photographic system consists of two cameras mounted at ports on the test chamber. One camera is used to take Polaroid pictures of the front of the test sample. These can be multiple arc exposures or a single arc. The second camera looks at the side edge of the sample. All ports are sealed to prevent extraneous light from entering the chamber.

If light is desired in the chamber to determine the influence of photo-effects, it can be provided by a quartz arc lamp mounted inside the chamber.

A luminescent screen can be mounted behind the test sample to watch the activity as the sample is being charged and discharged. This visual data must be recorded by an observer.

The test system apparatus and instrumentation generally used is given in Table 1.

2

3.0 TEST PROCEDURE

3.1 TEST SAMPLE

A sample number shall be assigned to each sample tested. A log shall be kept by the test engineer giving the number, a description of the sample, and the date(s) of the test. This information shall also be recorded on the test data sheets (see Figure 3).

3.2 TEST START

The facility chamber shall be at a pressure of 5×10^{-7} torr or less before testing can start. The actual pressure shall be recorded and the pressure instrumentation shall be turned off.

The center current sensor shall be lowered such that the grounded plate attached to the sensor completely shields the test sample from direct electron impingement. The electron gun shall be brought to a general operating condition for the current density desired (heater and bias supply). The high voltage supply shall be brought to the desired beam voltage and the heater and bias supplies shall be adjusted to bring the current density to the proper level and uniformity, as determined by the sensors. All sensor readings shall be recorded on the data sheet.

The oscillograph shall be turned on. The center probe shall be raised above the sample exposing the sample to the electron flux. The initial leakage current jump when the sample is first exposed shall be recorded as the zero time data point. This is the maximum displacement current.

3.3 TEST CONDITIONS

A survey test shall consist of exposing a sample to electrons accelerated through potentials of 5KV, 8KV, 10KV, 12KV, 14KV, 16KV, 18KV, and 20KV. The current density shall be 0.5 nanoamp/ cm², 1 nanoamp/cm², and 3 nanoamp/cm². Hence, 24 data sets are required to complete the survey.

The test shall be run in the following manner: the tests at the lowest current density shall be run first starting at the lowest beam voltage and progressing to the highest. Then, the test at the next highest current density shall begin starting at the lowest beam voltage and proceeding to the highest. A sample shall be exposed to a given current density and a specified beam voltage for 20 minutes. The leakage current value and the arc count shall be recorded on the data sheet every two minutes. During the 20 minutes of the test the following photographic data must be taken at least once (more photographs may be taken at the discretion of the operator):

a. Photograph of the antenna pickup of the discharge (if any);

b. Photograph of the leakage current transient (if any).

The photographs shall be marked with the test conditions, the test and sample identification, and the duration of exposure.

At the conclusion of the 20 minute period, the center current sensor shall be lowered and the data from the five sensors recorded. The test can then proceed to the next beam voltage level. NOTE: It is necessary to discharge the test sample completely after the 20KV test and before beginning the 5KV test at the next electron current density. This can be accomplished by operating the plasma source according to the established procedure.

The tank pressure shall be monitored periodically during the test when the center probe covers the sample. If the pressure rises above 5×10^{-7} torr, the test shall be terminated. The pressure instrumentation shall be turned off before further testing.

The photographs of the discharges (front and side) shall be limited to those beam voltages known to give visible discharges. Hence, verification of visible discharges will be required before photographs will be taken. This usually limits photographs to testing at beam voltages of 16KV or greater. The backs of the photographs shall be marked with the test and sample identification, the test condition, the duration of exposure, and the number of arcs.

3.4 EXTENDED DURATION TESTING

At the discretion of the test engineer an extended duration test can be run. The test conditions shall be specified by the engineer and the purpose of the test recorded in the log and on the data sheet.

The conditions at the start of the test shall be the same as those given in paragraph 3.2. During this test the following

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data shall be taken every 30 minutes: sample leakage current and arc count. Periodically during this test photographs shall be taken of the oscilloscope trace from the loop antenna and the leakage current transient. The oscillograph shall be on.

Every two hours during this test, the center current sensor shall be lovered. All current sensor data shall be recorded. If the electron gun has drifted from the original setting, it shall be readjusted to the prescribed value and the old and this new data shall be recorded.

4.0 TEST EFORT

The test engineer shall prepare a test report at the conclusion of each test. This report shall include identification of the test sample, the test dates, the purpose of the test, the test conditions, any test procedure pecularities or anomalies, the test data sheet, the photographs of the artenna and leakage current transients and a summary of the results. The summary of results shall include plots of the leakage currents when no discharges occurred and the computed value of the surface voltage for these conditions. For the test conditions in which there were discharges, a plot of the accumulated number of discharges versus beam voltage shall be provided.

If extended duration testing was conducted in addition to the survey, this information shall be included in the test report. A plot of arc count as a function of time shall be included.

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TABLE I. - TEST SYSTEM APPARATUS AND INSTRUMENTATION

Protection Circuitry:

Electron Gun:

Electron Gun Power Supplies and Controls:

Current Sensors:

Arc Level Discriminator:

Luminescent Screen:

Plasma Source:

Plasma Source Power Supplies and Controls:

Oscillograph:

Counter:

Electrometer:

Oscilloscopes:

LeRC design and manufacture LeRC design and manufacture

LeRC design and manufacture

LeRC design and manufacture

LeRC design and manufacture

LeRC design and manufacture

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Brush Instruments Mark 200 8-channel recorder

Berkeley Instruments, Inc. 6220 Dual Preset Counter

Keithley Instruments, Inc. Digital Electrometer Model 616

Tektronix, Inc. R7844 Dual Beam Oscilloscope Plug-in units: 7A16A Amplifier 7A14 Current Probe Amplifier 7M13 Readout Unit 7B92 Dual Time Base P6021 AC Current Probe C-50/C-70 Film Back (Roll Film)

Tektronix, Inc. 7633 Oscilloscope Plug-in units: 7A16A Amplifier 7M13 Readout Unit 7B53A Dual Time Base C-50/C-70 Film Back (Pack Film)

High Voltage Power Supply:

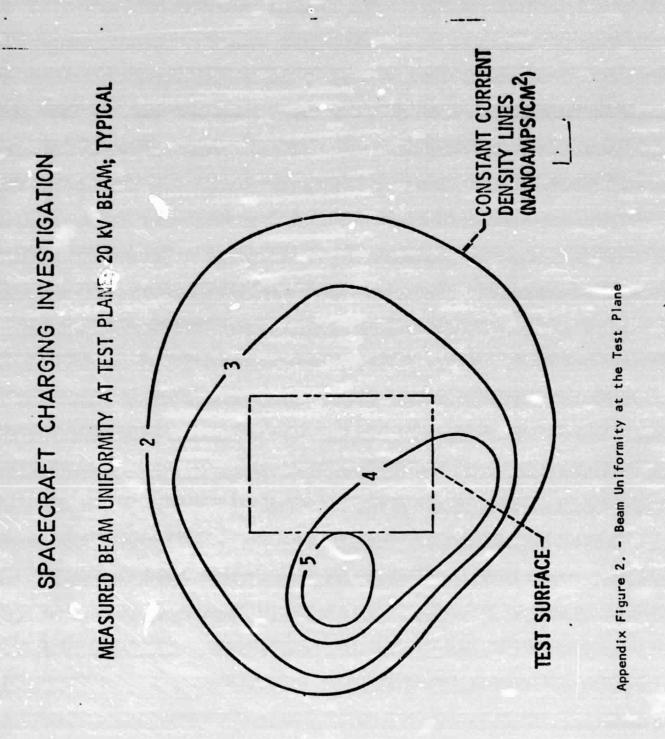
Beta Electric

COUNT SELECT EVEL LEAKAGE CURRENT SCOPE -LUMINESCENT SCREEN ARC. PROTECTION CURRENT PROBES SAMPLE --ш 9 사 SCOPE CURRENT PROBES--RECORDER LOOP ANTENNA ---LOOP ANTENNA -ELECTRON GUN VACUUM CHAMBER-SUPPLY BIAS 0-30 kV SUPPLY 11 SUPPLY FLY

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Appendix Figure 1. - Schematic of Test Facility

SPACECRAFT CHARGING EXPERIMENTAL FACILITY



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BEAM	BEAM					
		FILAMENT IT CURRENT (A)	GROUND CURRENT	BIAS VOLTAGE (Volts)	BIAS CURRENT	-TANK PRESSURE-
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KV	TEST				KV TES	r
" " " " " " " " " " " " " " " " " " "			PR	OBES INITIA		PROBE: //3 //4 //5
			0 2 4 6 8 10 12 14 16 18 20			
//2 IAL			PRO	DES INITIA	//2 L	PROBE: //3 //4 //5
1 S/	ANP. 1	OTAL > 2.5V	0 2 4 6 8 10 12 14 16	TIME	1 SAMP.	TOTAL > 2.5V
	: IAL I S 	initial initial initial initial		Image: Problement of the system of the s	Image: Second	Image: Second